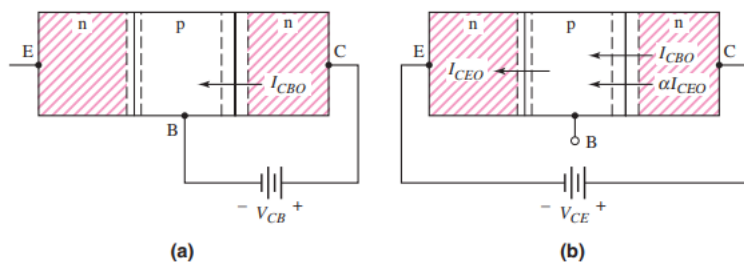


## Leakage currents in BJT

### Leakage Currents

In the common-base circuits in Figure 5.11, if we set the current source  $i_E = 0$ , transistors will be cut off, but the B–C junctions will still be reverse biased. A reverse-bias leakage current exists in these junctions, and this current corresponds to the reverse-bias saturation current in a diode, as described in Chapter 1. The direction of these reverse-bias leakage currents is the same as that of the collector currents. The term  $I_{CBO}$  is the collector leakage current in the common-base configuration, and is the collector-base leakage current when the emitter is an open circuit. This leakage current is shown in Figure 5.15(a).



**Figure 5.15** Block diagram of an npn transistor in an (a) open-emitter configuration showing the junction leakage current  $I_{CBO}$  and (b) open-base configuration showing the leakage current  $I_{CEO}$

Another leakage current can exist between the emitter and collector with the base terminal an open circuit. Figure 5.15(b) is a block diagram of an npn transistor in which the base is an open circuit ( $i_B = 0$ ). The current component  $I_{CBO}$  is the normal leakage current in the reverse-biased B–C pn junction. This current component causes the base potential to increase, which forward biases the B–E junction and induces the B–E current  $I_{CEO}$ . The current component  $\alpha I_{CEO}$  is the normal collector current resulting from the emitter current  $I_{CEO}$ . We can write

$$I_{CEO} = \alpha I_{CEO} + I_{CBO} \quad (5.19(a))$$

or

$$I_{CEO} = \frac{I_{CBO}}{1 - \alpha} \cong \beta I_{CBO} \quad (5.19(b))$$

## Transistor Datasheet BC547B

Parameters	Symbol	Test Condition	Value	Unit
Collector Emitter Voltage	$V_{CEO}$	$I_C = 1\text{mA}, I_B = 0$	>45	V
Collector Base Voltage	$V_{CBO}$	$I_C = 10\mu\text{A}, I_E = 0$	>50	
Emitter Base Voltage	$V_{EBO}$	$I_E = 10\mu\text{A}, I_C = 0$	>6.0	
(1+β) I <sub>CBO</sub> = I <sub>CEO</sub> Collector Cut off Current	$I_{CBO}$	$V_{CB} = 30\text{V}, I_E = 0$ $T_J = 150^\circ\text{C}$ $V_{CB} = 30\text{V}, I_E = 0$	<50 <5.0	nA μA
	$I_{CES}$	$V_{CE} = 50\text{V}, V_{BE} = 0$ $T_J = 125^\circ\text{C}$	<15	nA
Collector Cut off Current		$V_{CE} = 50\text{V}, V_{BE} = 0$	<4.0	μA
DC Current Gain $\beta = h_{FE}$	$h_{FE}$	$I_C = 2\text{mA}, V_{CE} = 5\text{V}$	200	-
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C = 10\text{mA}, I_B = 0.5\text{mA}$ $I_C = 100\text{mA}, I_B = 5\text{mA}$	<0.25 <0.60	V
Base Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C = 10\text{mA}, I_B = 0.5\text{mA}$ $I_C = 100\text{mA}, I_B = 5\text{mA}$	Typical 0.70 Typical 0.90	
Base Emitter On Voltage	$V_{BE(on)}$	$I_C = 2\text{mA}, V_{CE} = 5\text{V}$ $I_C = 10\text{mA}, V_{CE} = 5\text{V}$	0.55 - 0.70 <0.72	

$$V_{BE} = 0.7\text{V}$$

# BC547B

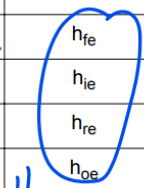
## General Purpose Transistor



### Electrical Characteristics ( $T_a = 25^\circ\text{C}$ unless otherwise specified)

Parameters	Symbol	Test Condition	Value	Units
<b>Dynamic Characteristics</b>				
Transition Frequency	$f_T$	$I_C = 10\text{mA}$ , $V_{CE} = 5\text{V}$ $f = 100\text{MHz}$	Typical 300	MHz
Collector Output Capacitance	$C_{cbo}$	$V_{CB} = 10\text{V}$ , $f = 1\text{MHz}$	<4.50	pF
Emitter Input Capacitance	$C_{ib}$	$V_{EB} = 0.5\text{V}$ , $f = 1\text{MHz}$	Typical 9.0	
Noise Figure	NF	$I_C = 0.2\text{mA}$ , $V_{CE} = 5\text{V}$ $R_s = 1\text{k}\Omega$ , $f = 200\text{Hz}$	<10	dB
Small Signal Current Gain	$h_{fe}$	$I_C = 2\text{mA}$ , $V_{CE} = 5\text{V}$	Typical 330	-
Input Impedance	$h_{ie}$		3.2 - 8.5	$\text{k}\Omega$
Voltage Feedback Ratio	$h_{re}$		Typical 2.0	$\times 10^{-4}$
Output Impedance	$h_{oe}$		<60	$\mu\Omega$

$$\beta_{ac} = h_{fe}$$



h-parameter model

### Specifications

## Transistor Biasing

### 1.10 TRANSISTOR BIASING

The basic function of a transistor is to do amplification. The weak signal is given to the transistor and amplified output is obtained from collector. The process of raising the strength of weak signal without any

change in its general shape is known as faithful amplification. The basic problems involved in the design of transistor circuits is establishing and maintaining the proper collector to emitter voltage and collector current in the circuit. This condition is known as transistor biasing. The biasing conditions must be maintained despite variations in temperature, variations in gain and leakage current and variation in supply voltages.

### Necessity of Transistor Biasing:

#### 1.10.1 Necessity of Biasing

For faithful amplification, following conditions must be satisfied:

- Proper zero signal collector current ( $I_C$ )
- Proper base emitter voltage ( $V_{BE}$ )
- Proper collector-emitter voltage ( $V_{CE}$ )

The value of  $I_C$  and  $V_{CE}$  is expressed in terms of operating point or quiescent point Q. For faithful amplification, Q point must be selected properly. The fulfillment of the above conditions is known as transistor biasing.

## Need for Stabilization

### 1.10.2 Need For Stabilization (Why Q-Point Changes)

The collector current  $I_C$  depends on reverse saturation current  $I_{CO}$ , current gain  $\beta$  and base emitter voltage  $V_{BE}$ . These parameters are temperature dependent i.e. as temperature changes, these parameters change. Hence collector current  $I_C$  changes. Due to this, Q point changes. Hence Q point has to be stabilized against temperature variation.

✓ (1)  $I_{CO}$  : The collector current is given by

$$I_C = \beta I_B + (\beta + 1) I_{CO}$$

$$I_{CO} \leftarrow \begin{matrix} I_{CBO} \\ I_{CEO} \end{matrix}$$

The collector leakage current  $I_{CO}$  doubles for every  $10^\circ\text{C}$  rise in temperature. The flow of collector current produces heat at the collector junction. This increases the temperature, therefore leakage current  $I_{CO}$  increases. Hence, collector current  $I_C$  again increases. This increase in  $I_C$  increases temperature of collector junction which increases  $I_{CO}$  again. The effect is cumulative and at one stage  $I_C$  is so large which damages the transistor. This process is known as **thermal runaway**.

(2)  $\beta$  : The transistor parameter  $\beta$  is temperature and device dependent.  $\beta$  increases with the increase in temperature. Value of  $\beta$  is different even for transistors of same type. If transistor is replaced by another transistor even of the same type, the value of  $\beta$  is different. Hence, collector current changes. Therefore, Q-point changes.

$$S_\beta \approx S'$$

(3)  $V_{BE}$  : The base emitter voltage  $V_{BE}$  decreases at the rate of  $2.5 \text{ mV}/^\circ\text{C}$  i.e. device starts operating at lower voltages. Hence, base current changes which changes collector current and hence the Q-point.

$$S_{V_{BE}} \approx S''$$

The process of stabilizing Q-point is called as thermal stabilization. There are three methods to bias the BJT.

- (1) Fixed bias
- (2) Collector to base bias
- (3) Voltage divider bias

ChatGPT  
"Thermal  
Runaway"  
in a BJT

Not in  
syllabus

### 1.10.3 Stability Factor (S)

The rate of change of collector current w.r.t. collector leakage current  $I_{CO}$  at constant  $\beta$  and  $V_{BE}$  is called as stability factor.

$$\text{Stability factor } S = \left. \frac{\partial I_C}{\partial I_{CO}} \right|_{\beta, V_{BE} = \text{constant}}$$

$$I_{CO} \begin{cases} I_{CBO} \\ I_{CEO} \end{cases}$$

**Expression for stability factor**

We know that,  $I_C = \beta I_B + (\beta + 1) I_{CO}$

Differentiating w.r.t.  $I_C$ ,

$$1 = \beta \frac{\partial I_B}{\partial I_C} + (\beta + 1) \frac{\partial I_{CO}}{\partial I_C}$$

$$1 - \beta \frac{\partial I_B}{\partial I_C} = (\beta + 1) \frac{\partial I_{CO}}{\partial I_C} = \frac{(\beta + 1)}{\frac{\partial I_C}{\partial I_{CO}}}$$

$$1 - \beta \frac{\partial I_B}{\partial I_C} = \frac{(\beta + 1)}{S}$$

$$S = \frac{\beta + 1}{1 - \beta \frac{\partial I_B}{\partial I_C}}$$

$S_{I_{CO}}$